Trace elements in silicate melts at high pressure

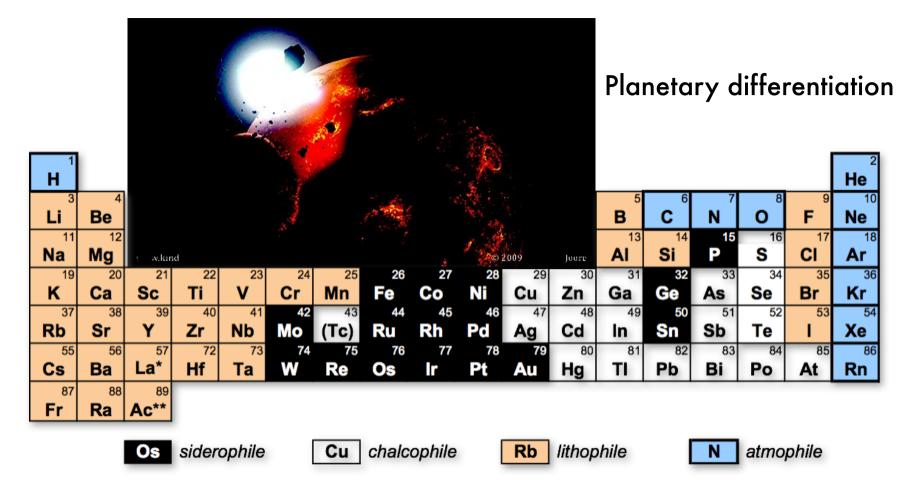
C. SANLOUP, C. Crépisson, C. Leroy, C. de Grouchy, B. Cochain, L. Cormier

IMPMC, Sorbonne Université University of Edinburgh, School of Physics





ELEMENT DISTRIBUTION DURING PLANETARY MELTING



Does pressure affect the geochemical affinity of elements with silicate melts?

→ compatible/incompatible: crust formation ¹⁷⁶Lu/¹⁷⁶Hf, ¹⁴⁶Sm/¹⁴²Nd, ¹⁸²Hf/¹⁸²W → lithophile/volatile: atmosphere formation ¹²⁹I/¹²⁹Xe **Exploring silicate melt structure at high P-T conditions**

Informations:

1) First coordination shell: interatomic distance, nature of neighbouring atoms, coordination number, oxidation state

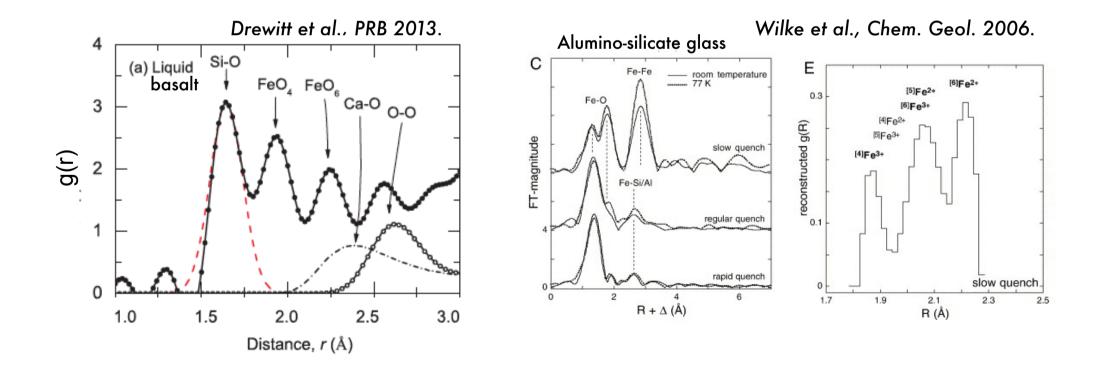
2) mid-range order (XRD), second coordination shell (XRD, XAS)

X-ray diffraction:

All elements contribute to signal

X-ray absorption spectroscopy:

Chemically selective, model dependent



Trace and minor elements in magmas: experimental approaches

X-ray diffraction:

All elements contribute to signal Restrictions: only very heavy elements Fe-free compositions

Elements: Lu, Nd, Xe

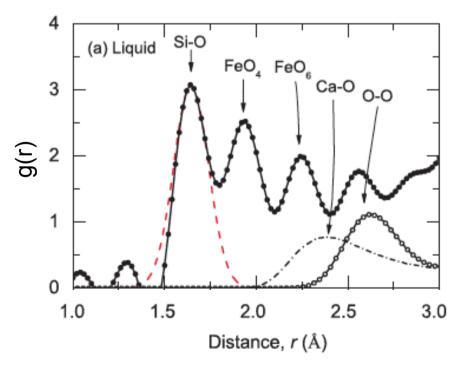
X-ray absorption spectroscopy:

Chemically selective, model dependent Restrictions: 11 keV < energy < 30 keV

Elements: W, Nb, Br, Kr

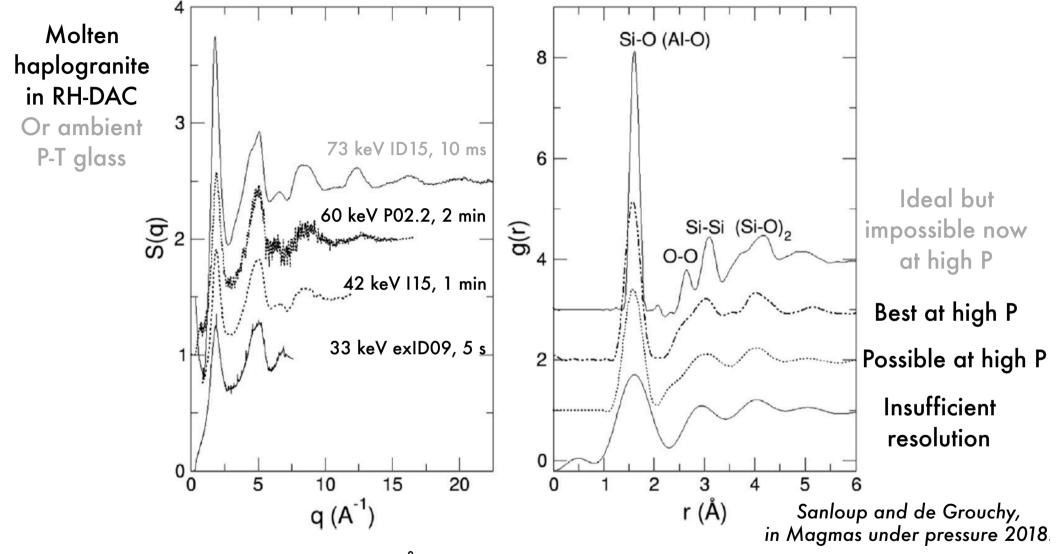
Major oxide components in silicate melts:

	SiO ₂	AI_2O_3	FeO	MgO	CaO	Na ₂ O	K ₂ O	H ₂ O
granite	76%	13%	2%	0.5%	2.5%	3%	2%	
haplogranite	68%	11%	-	-	-	4%	3%	15%
basalt	50%	15%	8%	8%	13%	2%	2%	



Drewitt et al., PRB 2013.





Window between 1.8-2.5 Å: where many key trace elements are expected

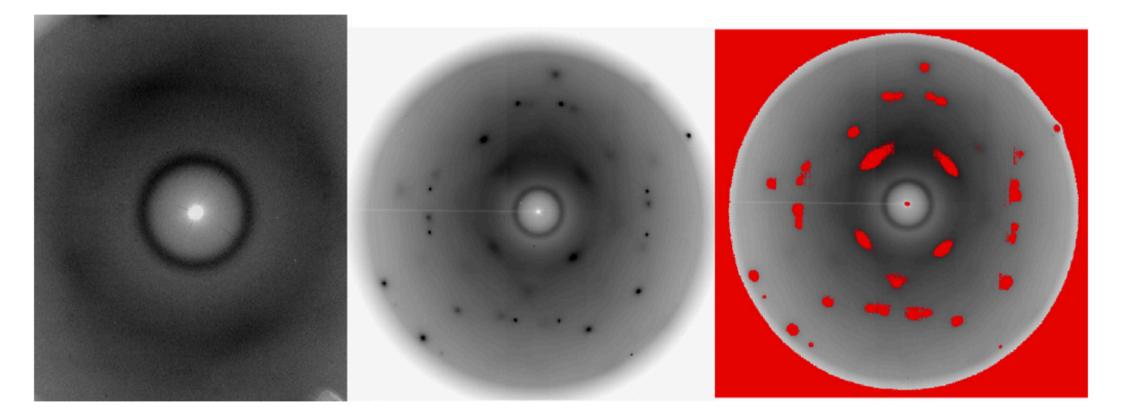
Requirement of a sufficiently large q-range:

high-energy angle dispersive XRD in DACs or energy dispersive XRD in large volume presses

Probing trace elements in melts at high P-T conditions using XRD

Angle-dispersive x-ray diffraction and DACs:

correction for diamonds Bragg peaks is significant at high energies

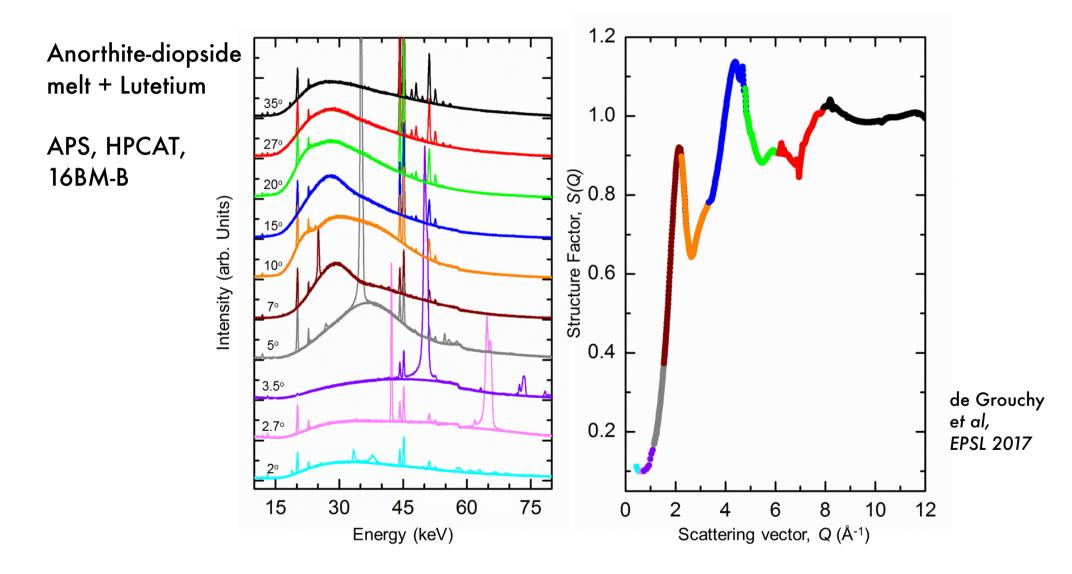


33 keV, MAR555

60 keV, Perkin-Elmer

Probing trace elements in melts at high P-T conditions using XRD





NB: some elements may have strong fluorescence peaks that need to be removed

Exploring silicate melt structure at high P-T conditions

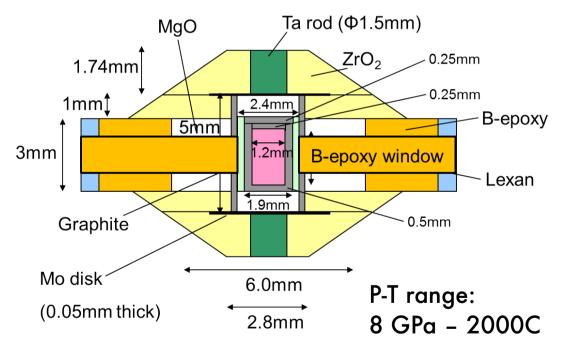
Resistive heating DACs:

Optimizing sample volume Large opening DACs, e.g. Boelher-Almax anvils

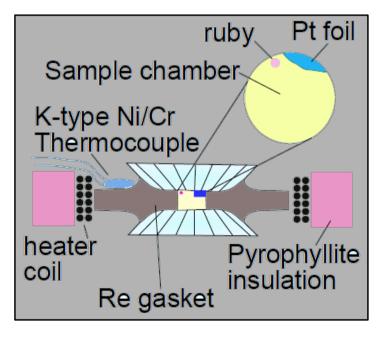
Need hydrated glasses to lower melting T

Paris-Edinburgh press:

Same cell-assembly used for XRD and XAS (provided by the APS)



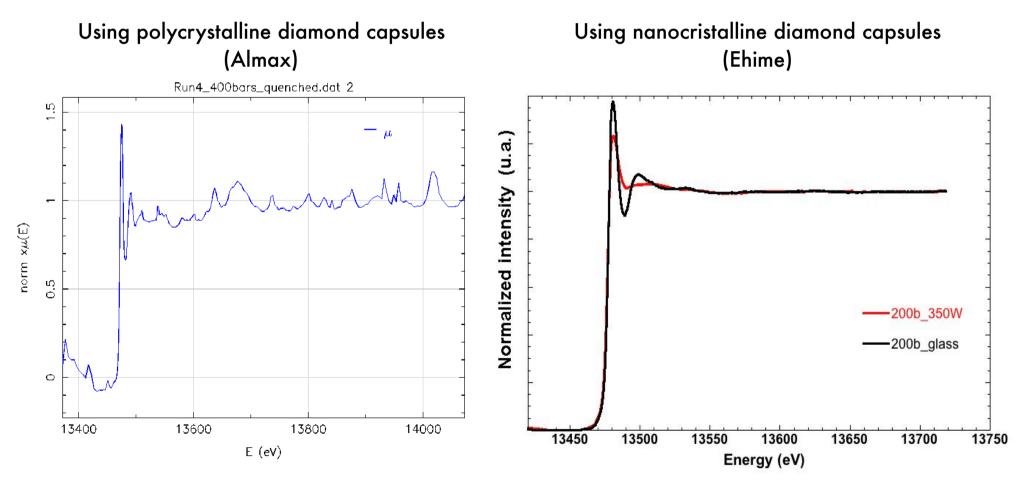
High stability at high T, large vertical access



X-ray absorption spectroscopy at high P-T conditions

Requires nanocristalline diamond capsules or anvils PRIUS programme, GRC Ehime University (Pr. Irifune)

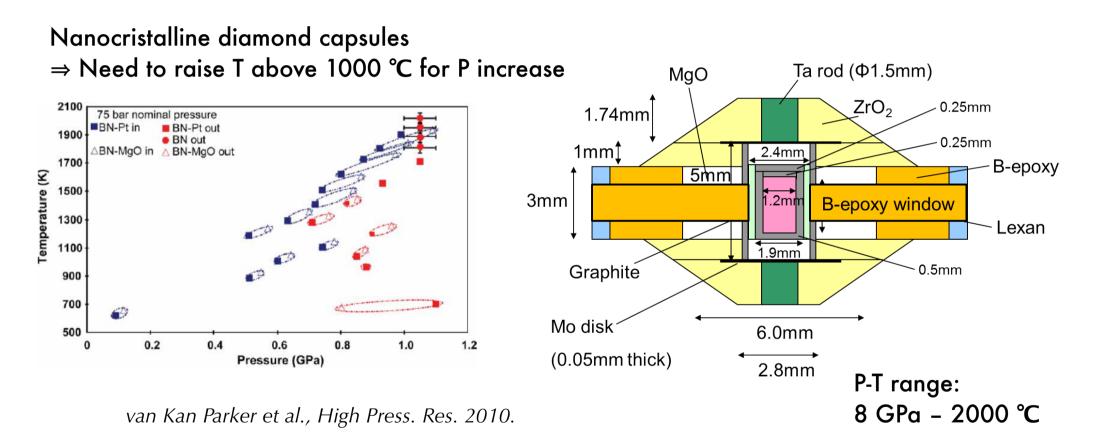
Br-dopped (0.4 at%) dacitic melt



Cochain et al. Chem Geol 2015

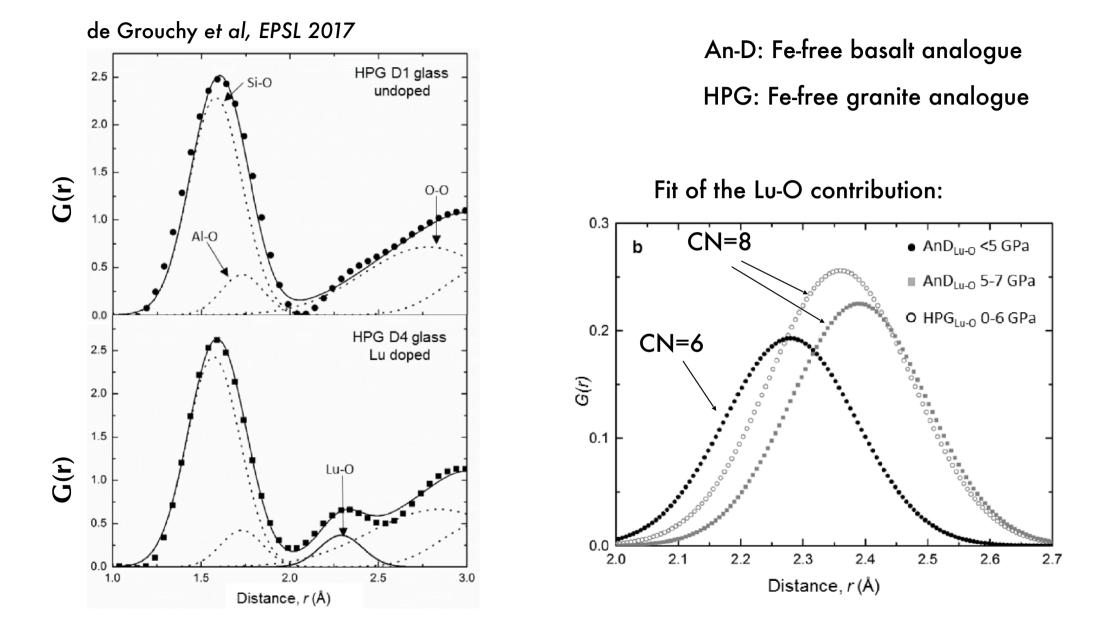
X-ray absorption spectroscopy using a Paris-Edinburgh press

Long collection times (3 hours) ⇒ Need high stability cell-assembly and large vertical gap to optimise signal/noise ratio



Use of Pt-Rh or graphite caps: Possibility to buffer the redox state (also talc powder outside caps)

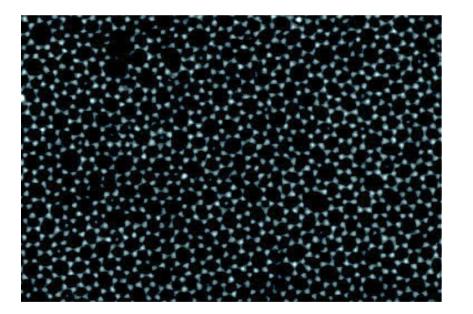
Lutetium - X-ray diffraction in DACs (Diamond, 115) and PE press (HPCAT)



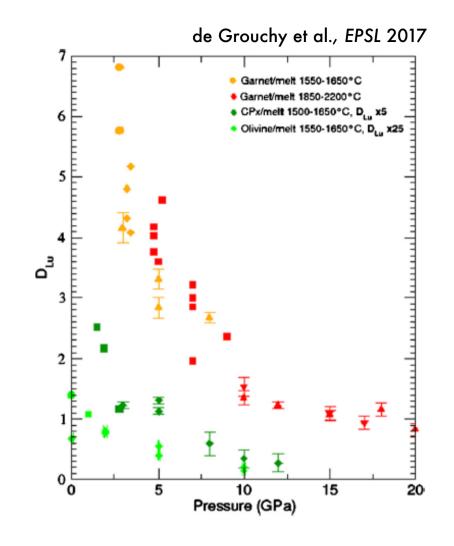
 \Rightarrow Lu-O coordination change in basalts: from 6 to 8 at 4-5 GPa

Changes of environment of Lu, Nd in melts at high P: summary

- Lu-O: CN changes from 6 to 8 at ${\sim}4\text{-}5$ GPa
- Coincides with change of P-dependence in crystal/melt partitioning
- Nd-O: CN changes from 6 to 8 at ${\sim}1{\text{-}2}$ GPa



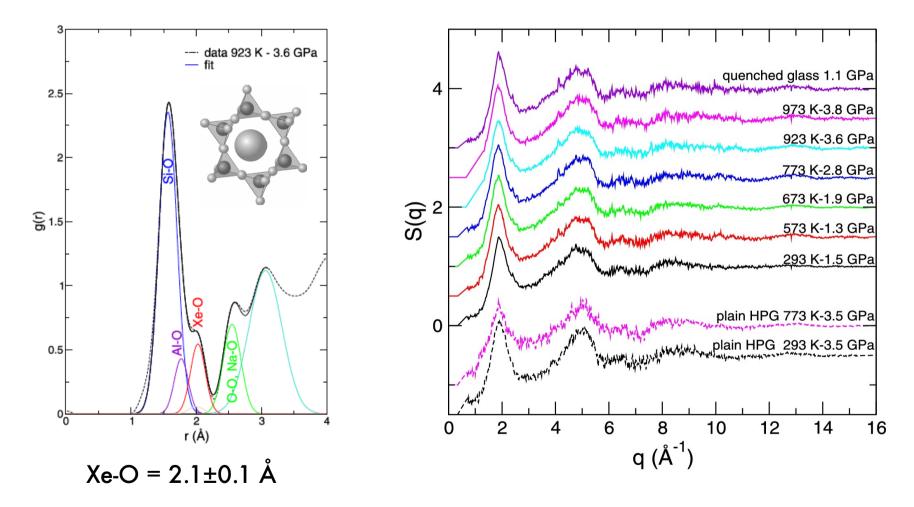
SiO₂ glass layer, TEM Huang et al., Nano Lett., 2012



- ⇒ D_{Lu}/D_{Hf} ~ 1 above 5 GPa: Lu and Hf should not be fractionated in high P basalts
- ⇒ Decoupling of Lu/Hf and Nd/Sm systems for high P melts

Reactivity of xenon and krypton in magmas

X-ray diffraction @ 60 keV, PetraIII (Hambourg) Haplogranite melt



 \Rightarrow similar distance in crystals, but different CN

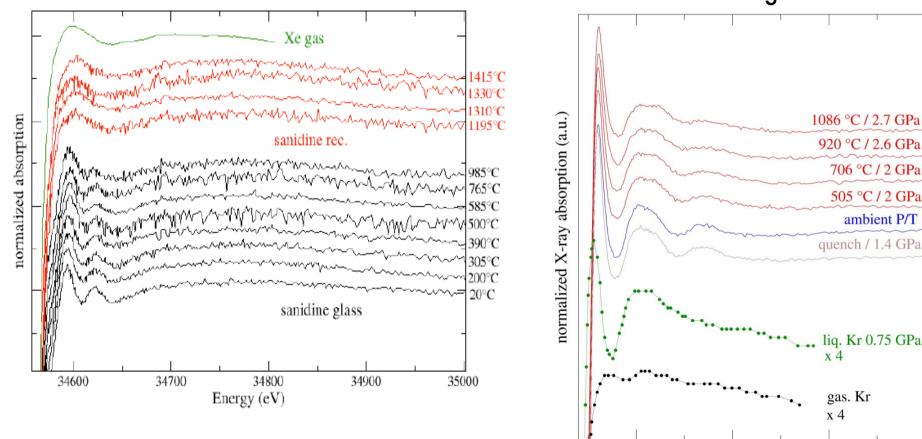
Leroy et al. EPSL 2018

Reactivity of xenon and krypton in magmas

EXAFS, ESRF (BM23) Glass and molten feldspar (sanidine) doped with Xe:Kr gas

Xe edge





Crépisson et al. Chem Geol 2018

14450

14500

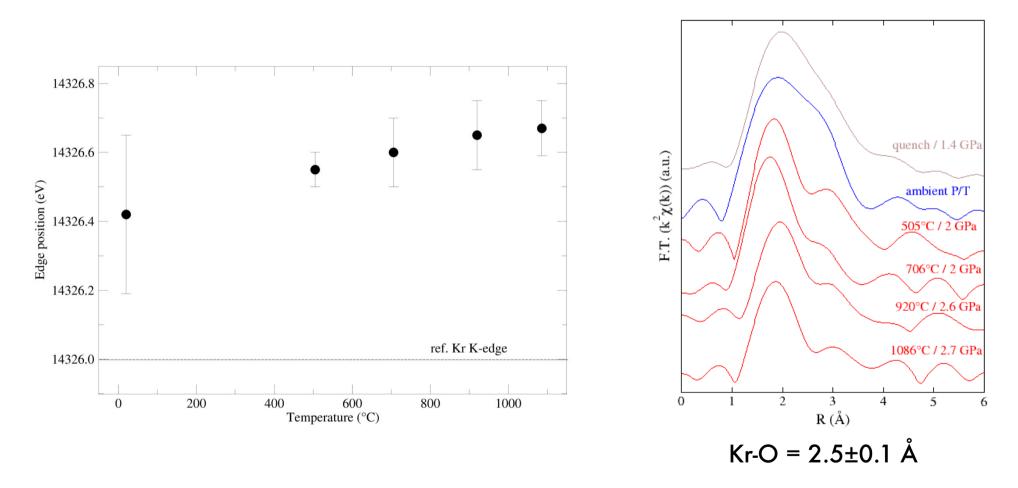
14400

Energy (eV)

14350

Reactivity of xenon and krypton in magmas

EXAFS, ESRF (BM23) Glass and molten feldspar (sanidine) doped with Xe:Kr gas



⇒ Kr also gets oxidized under pressure

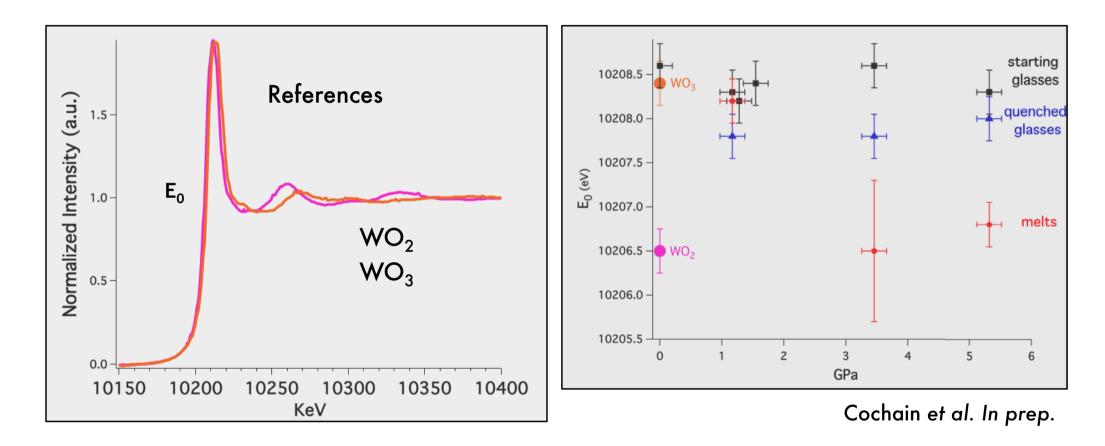
Crépisson et al. Chem Geol 2018

Tungsten - X-ray absorption in Paris-Edinburgh press (ESRF, BM23)

Basalt +0.6 wt% W

 \Rightarrow

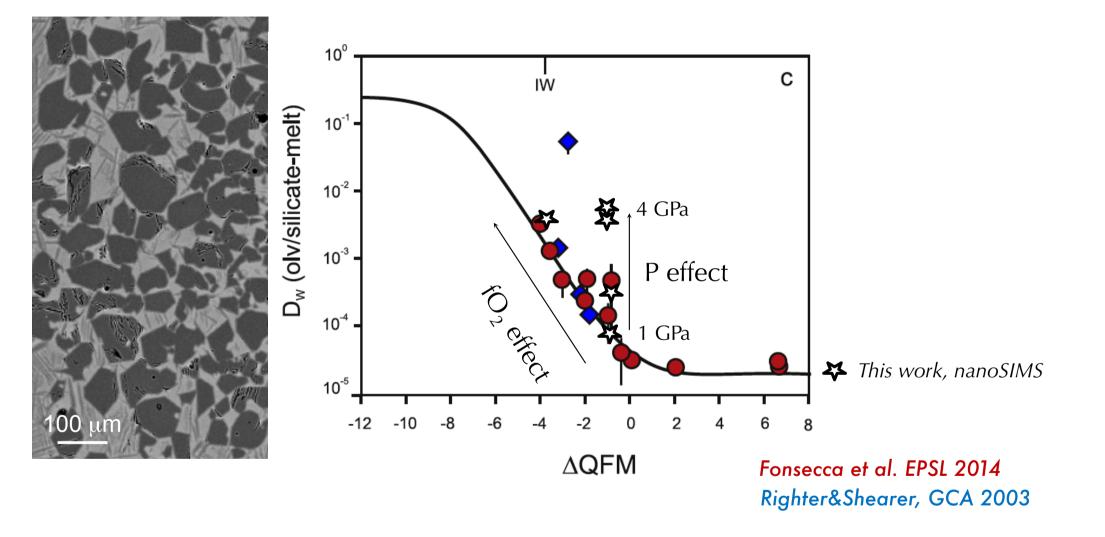
• Current debate on change from W⁶⁺ to W⁴⁺ with pressure



⇒ Reduction of W in the melt around 2-3 GPa

Not preserved in the quenched glass

Tungsten – Effect of oxidation state on partitioning



High pressure residues have high [W]

 \Rightarrow

Trace elements in melts: perspectives opened by the EBS

X-ray diffraction:

Currently limited to upper mantle studies for trace elements

EBS:

Much shorter collection times at high energy (>60 keV) Better focussing at high energy ⇒ compatible with laser heating DAC

X-ray absorption spectroscopy:

Chemically selective, model dependent Restrictions: 11 keV < energy <30 keV

EBS:

Higher energies accessible at high P-T Real 'trace' elements studies instead of 1% concentrations, *i.e.* <0.1 at%

Eventually also using LH-DACs

 \Rightarrow Opens applications to the whole terrestrial P-T range

(i.e. deep mantle reservoirs, core formation) with natural concentrations

Thanks for provision of beamtime: APS HPCAT 16BM-B, ESRF BM23, Diamond I15

Contributed to this work:

for synchrotron experiments: D. Daisenberg¹, I. Kantor², Y. Kono³, Z. Konopkova⁴, K. Glazyrin⁴, A. Rosa²

> for nano-SIMS analysis: M. Roskosz⁵

¹Diamond Light Source, ² ESRF, ³ HPCAT, Carnegie Institution of Washington now at Ehime University, ⁴DESY, ⁵Museum National d'Histoire Naturelle



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